



USG170N10

POWER MOSFET

170A, 100V N-CHANNEL POWER MOSFET

■ DESCRIPTION

The UTC **USG170N10** is a N-channel Power MOSFET, it uses UTC's advanced technology to provide the customers with low $R_{DS(ON)}$ characteristic by high cell density trench technology.

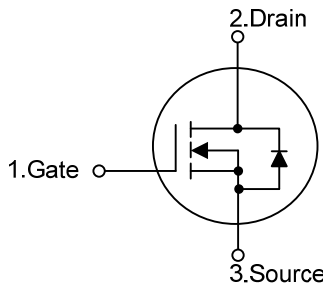
The UTC **USG170N10** is suitable for high efficiency synchronous rectification in SMPS, UPS, hard switched and high frequency circuits.

■ FEATURES

* $R_{DS(ON)} \leq 3.5 \text{ m}\Omega @ V_{GS}=10V, I_D=20A$

* High Switching Speed

■ SYMBOL



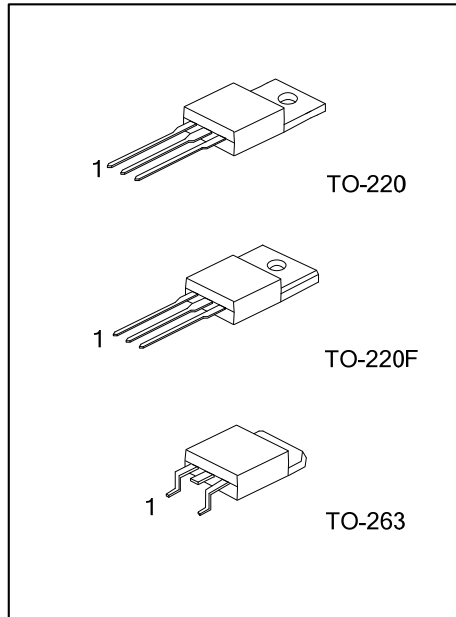
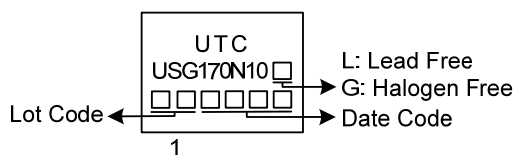
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
USG170N10L-TA3-T	USG170N10G-TA3-T	TO-220	G	D	S	Tube
USG170N10L-TF3-T	USG170N10G-TF3-T	TO-220F	G	D	S	Tube
USG170N10L-TQ2-T	USG170N10G-TQ2-T	TO-263	G	D	S	Tube
USG170N10L-TQ2-R	USG170N10G-TQ2-R	TO-263	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>USG170N10G-TA3-T</p>	<p>(1) T: Tube, R: Tape Reel</p> <p>(2) TA3: TO-220, TF3: TO-220F, TQ2: TO-263</p> <p>(3) G: Halogen Free and Lead Free, L: Lead Free</p>
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■ MARKING



■ ABSOLUTE MAXIMUM RATING ($T_C=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Drain-Source Voltage	V_{DSS}	100	V
Gate-Source Voltage	V_{GSS}	± 20	V
Drain Current	Continuous	I_D	170
	Pulsed (Note 2)	I_{DM}	340
Single Pulsed Avalanche Energy (Note 3)	E_{AS}	371	mJ
Peak Diode Recovery dv/dt (Note 4)	dv/dt	3.9	V/ns
Power Dissipation	TO-220/TO-263	P_D	180
	TO-220F		55
Junction Temperature	T_J	+150	$^{\circ}\text{C}$
Storage Temperature Range	T_{STG}	-20 ~ +150	$^{\circ}\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L=0.1\text{mH}$, $I_{AS}=86.2\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\ \Omega$, Starting $T_J = 25^{\circ}\text{C}$

4. $I_{SD} \leq 30\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^{\circ}\text{C}$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	62.5	$^{\circ}\text{C}/\text{W}$
Junction to Case	TO-220/TO-263	θ_{JC}	0.69 (Note)
	TO-220F		2.2 (Note)

Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

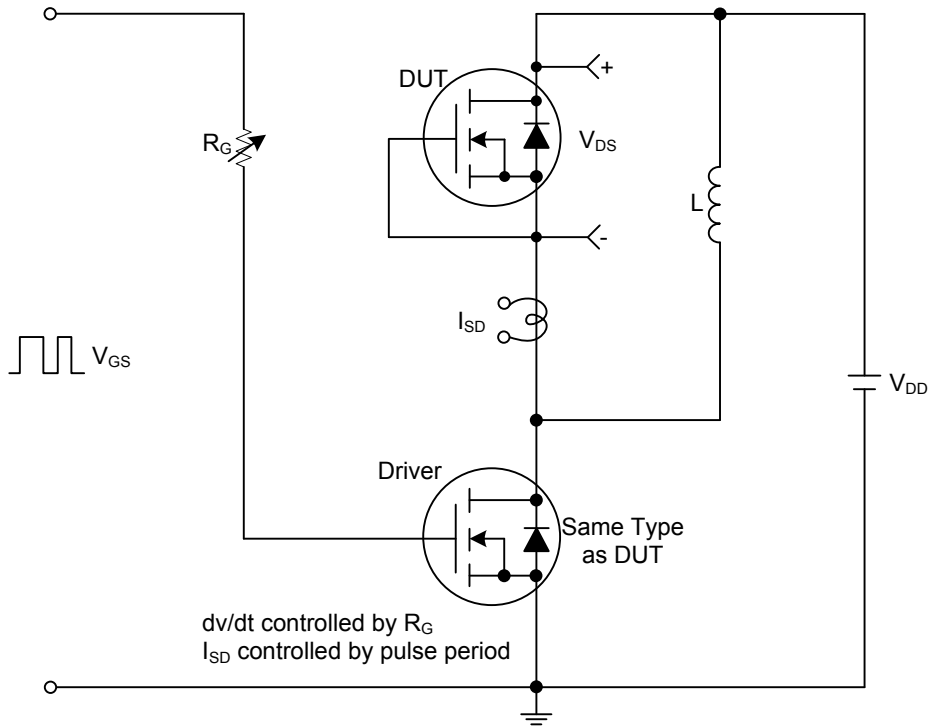
■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =250μA, V _{GS} =0V	100			V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =100V, V _{GS} =0V			1	μA
Gate-Source Leakage Current	Forward	I _{GSS}			+100	nA
	Reverse				-100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	2.0		4.0	V
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =20A		2.8	3.5	mΩ
DYNAMIC PARAMETERS						
Input Capacitance	C _{ISS}	V _{GS} =0V, V _{DS} =25V, f=1.0MHz		5500		pF
Output Capacitance	C _{OSS}			3300		pF
Reverse Transfer Capacitance	C _{RSS}			270		pF
SWITCHING PARAMETERS						
Total Gate Charge (Note 1)	Q _G	V _{DS} =80V, V _{GS} =10V, I _D =20A, I _G =1.0mA (Note 1, 2)		117		nC
Gate to Source Charge	Q _{GS}			24		nC
Gate to Drain Charge	Q _{GD}			38		nC
Turn-on Delay Time (Note 1)	t _{D(ON)}	V _{DD} =50V, V _{GS} =10V, I _D =20A, R _G =10Ω (Note 1, 2)		40		ns
Rise Time	t _R			32		ns
Turn-off Delay Time	t _{D(OFF)}			112		ns
Fall-Time	t _F			35		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS						
Maximum Body-Diode Continuous Current	I _S				170	A
Maximum Body-Diode Pulsed Current	I _{SM}				340	A
Drain-Source Diode Forward Voltage (Note 1)	V _{SD}	I _S =20A, V _{GS} =0V			1.3	V
Reverse Recovery Time (Note 1)	t _{rr}	I _S =30A, V _{GS} =0V, dI _F /dt =100A/μs		86		nS
Reverse Recovery Charge	Q _{rr}			238		nC

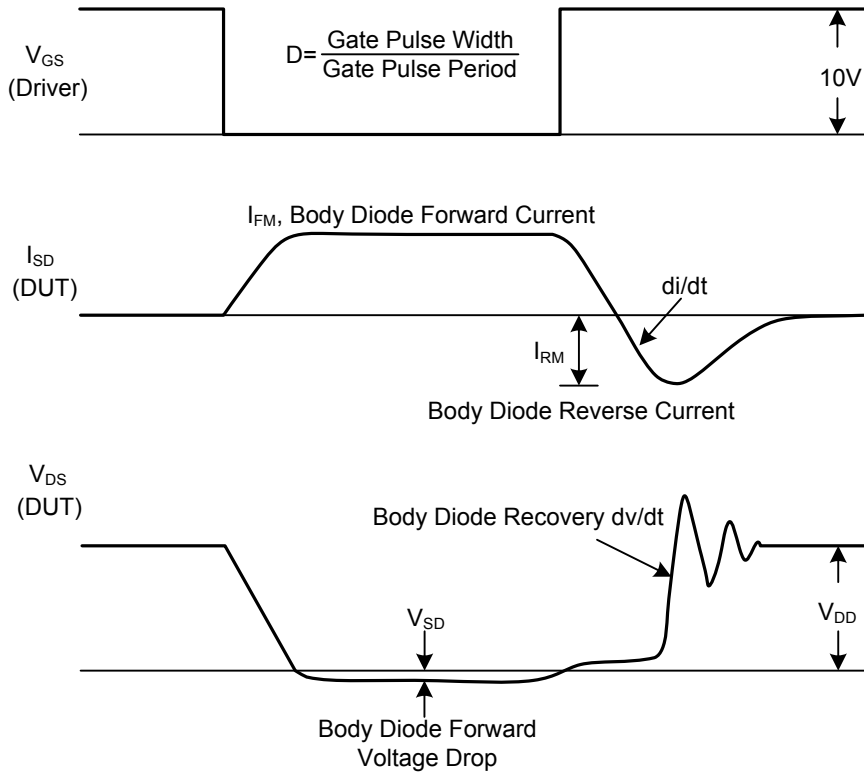
Notes: 1. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2%.

2. Essentially independent of operating ambient temperature.

TEST CIRCUITS AND WAVEFORMS



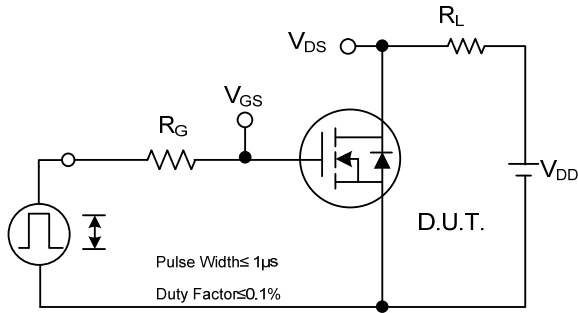
Peak Diode Recovery dv/dt Test Circuit



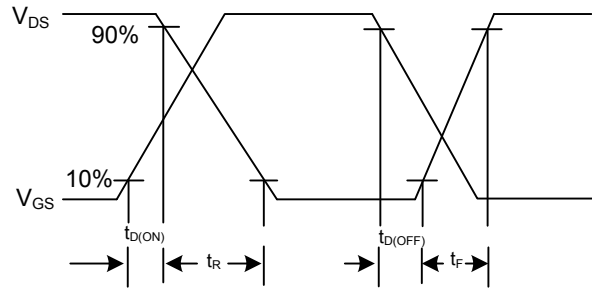
Peak Diode Recovery dv/dt Test Circuit and Waveforms

Peak Diode Recovery dv/dt Waveforms

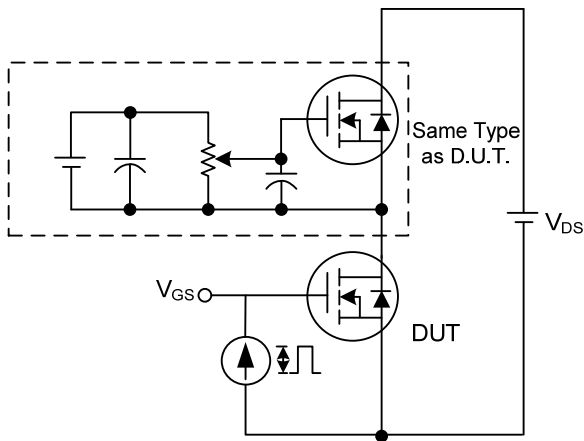
TEST CIRCUITS AND WAVEFORMS



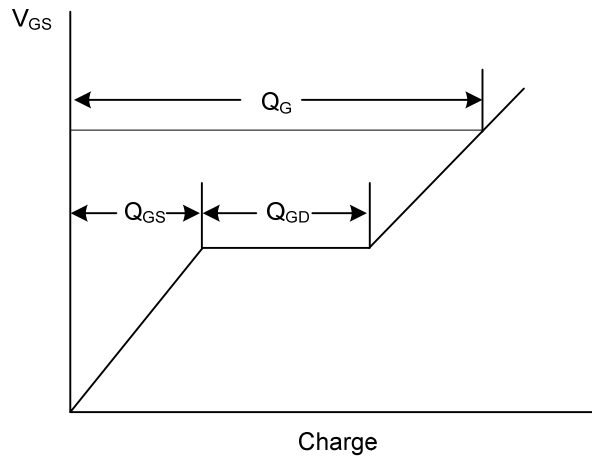
Switching Test Circuit



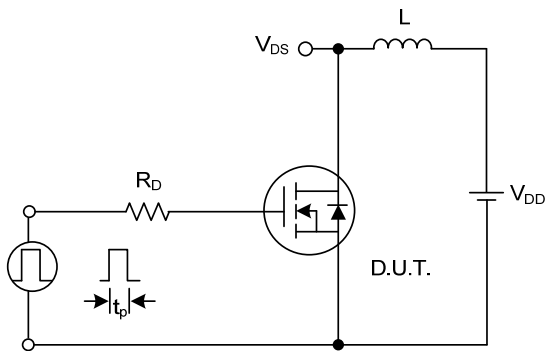
Switching Waveforms



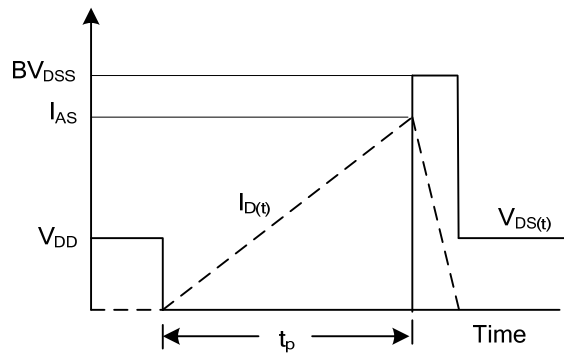
Gate Charge Test Circuit



Gate Charge Waveform

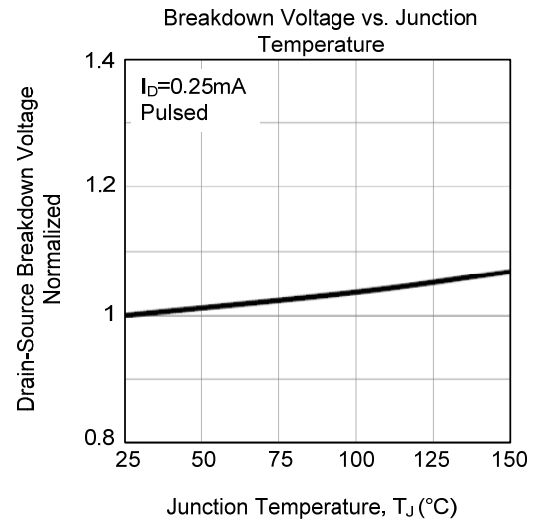
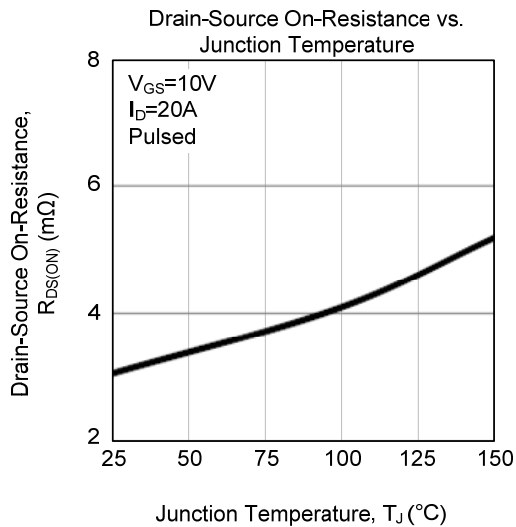
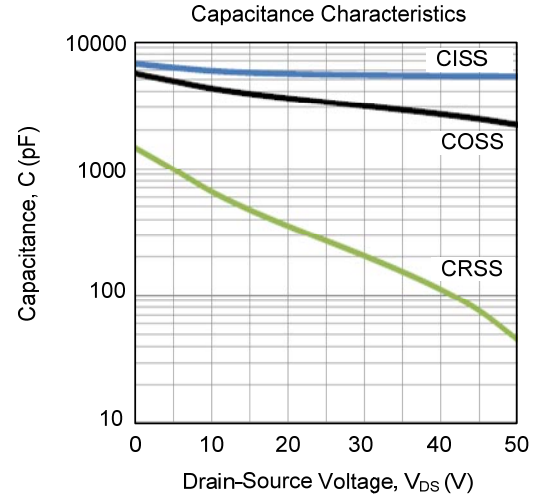
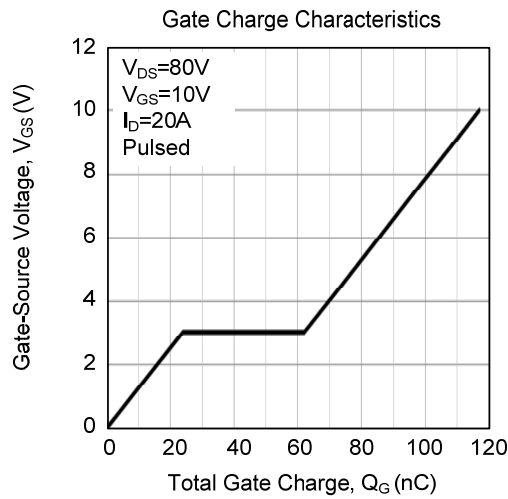
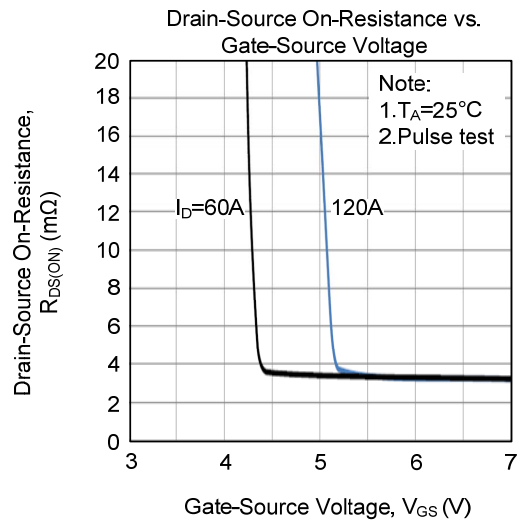
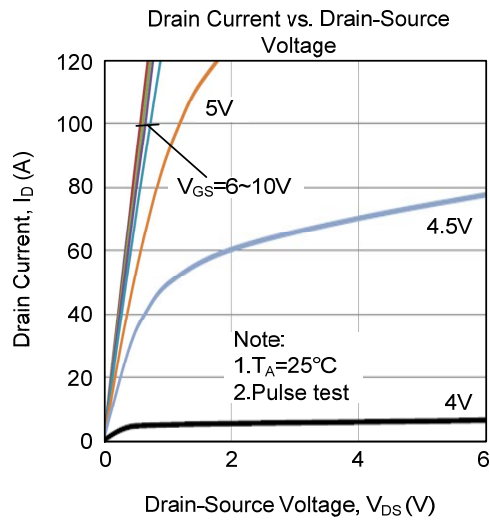


Unclamped Inductive Switching Test Circuit

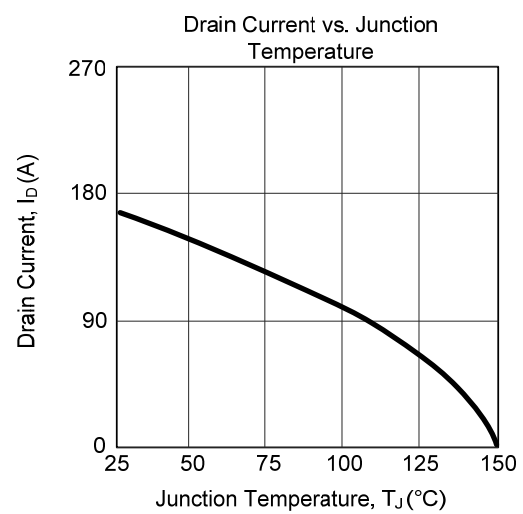
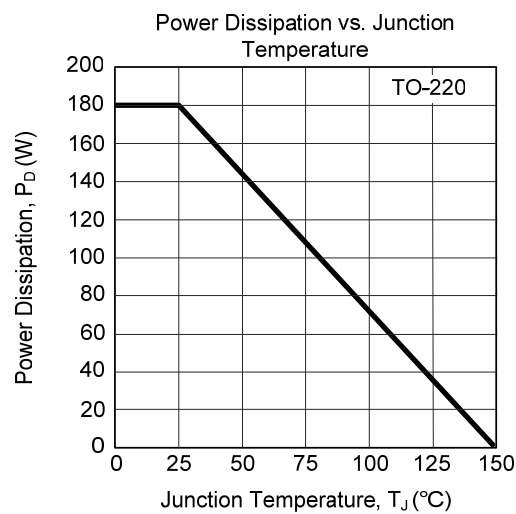
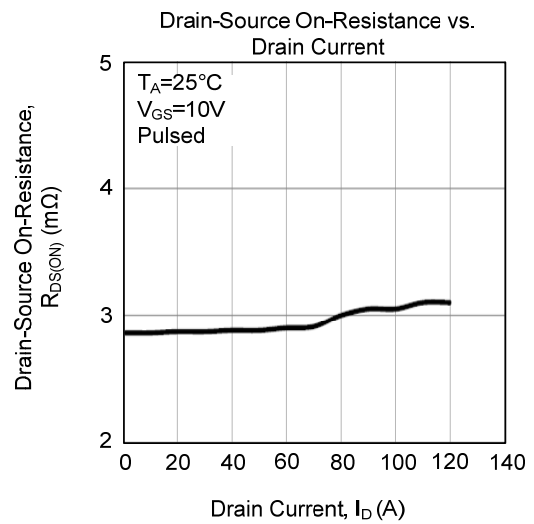
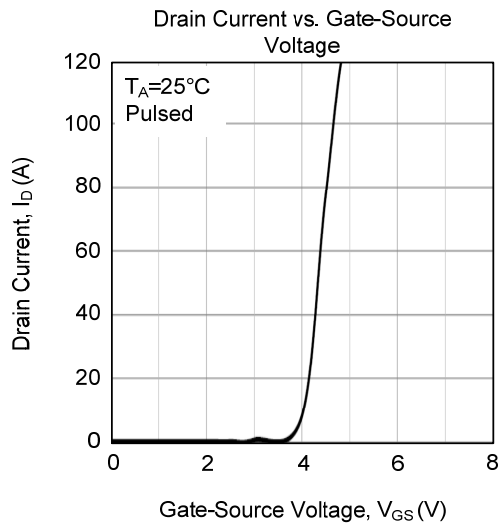
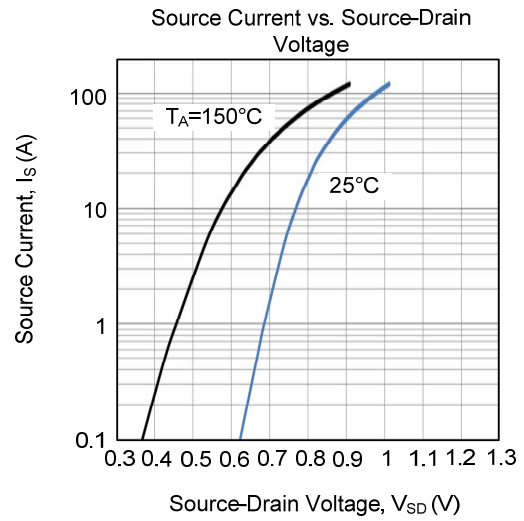
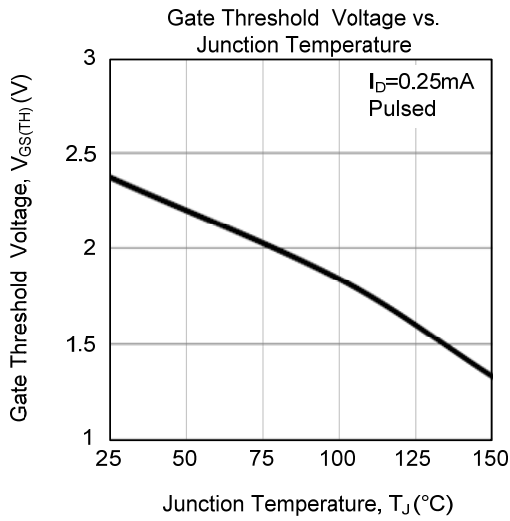


Unclamped Inductive Switching Waveforms

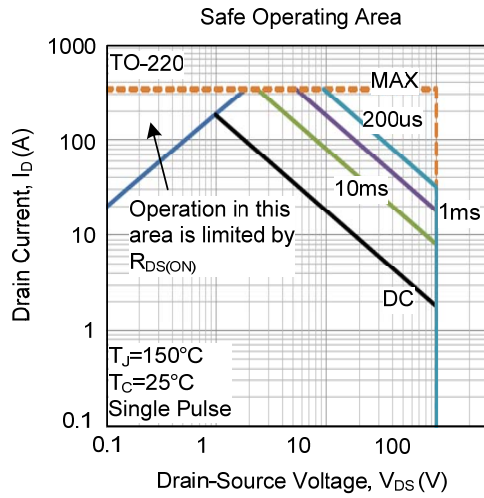
TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS (Cont.)



■ TYPICAL CHARACTERISTICS (Cont.)



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